Supporting Information

## Understanding the influence of Bi/Sb substitution on carrier concentration in Mg<sub>3</sub>Sb<sub>2</sub>-based materials: Decreasing bandgap enhances the degree of impurity ionization

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## Supplementary Table

**Table S1** The sample density (d) of  $Mg_{3.175}Mn_{0.025}Sb_{1.96-x}Bi_xTe_{0.04}$  measured by Archimedes method.

Samples	Density (g/cm <sup>3</sup> )	Relative density (%)
x=0.48	4.4	97%
<i>x</i> =1.2	5.03	95%
<i>x</i> =1.44	5.28	93%

## Supplementary Figure



**Fig. S1** The optimized crystal structures of  $Mg_3Sb_{2-x}Bi_x$  (*x*=0, 1 and 2).